

<b>Notice of References Cited</b>	Application/Control No. 10/796,607		Applicant(s)/Patent Under Reexamination LIN ET AL.	
	Examiner Prabodh M. Dharia		Art Unit 2629	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,088,340	08-2006	Kato, Syunji	345/168
*	B	US-2004/0108994	06-2004	Kato, Syunji	345/171
*	C	US-2005/0052425	03-2005	Zadesky et al.	345/173
*	D	US-2002/0140679	10-2002	Wen, Tai Chun	345/168
*	E	US-6,911,970	06-2005	Wen, Tai Chun	345/168
*	F	US-6,727,891	04-2004	Moriya et al.	345/169
*	G	US-6,587,587	07-2003	Altman et al.	382/181
*	H	US-2006/0028455	02-2006	Hinckley et al.	345/173
*	I	US-2002/0176245	11-2002	Fuwausa et al.	362/84
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2003-015808	01-2003	Japan	Kato Shunji	345/168
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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